Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/541,336	SHIRAISHI ET AL.
Examiner	Art Unit

Quang T. Van

3742

SEARCHED						
Class	Subclass	Date	Examiner			
373	93,91,92	8/22/06	av			
	51,105					
428	408					
266	46					
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Eastsearch	8/22/08	æv		
East search Inventor cheek	8/22/06	ar		
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